## AMENDMENTS TO THE CLAIMS

The status of the claims of the present application stands as follows:

Claims 1-18 (Canceled)

- 19. (Currently Amended) A method for scrubbing an exhaust gas of a manufacturing process, the exhaust gas comprising a first chemical component and a second chemical component, comprising the steps of:
  - a. flowing the exhaust gas through an enclosure defining a chamber and containing at least one substrate;
  - b. baffling, using said at least one substrate, the exhaust gas within said chamber so
    as to increase the residence time of the exhaust gas within said chamber; and
  - bc. causing the first chemical component to be chemical vapor deposited onto said at least one substrate.
- 20. (Currently Amended) A method according to claim 19, further comprising the step of removing the second chemical component from the exhaust gas after performing step bc).
- 21. (Currently Amended) A method according to claim 19, wherein step bc) is performed by heating at least one of said at least one substrate and said enclosure to at least 800°C.
- 22. (Currently Amended) A method according to claim 21, wherein step bc) is performed by heating at least one of said at least one substrate and said enclosure to at least 1100°C.
- 23. (Original) A method according to claim 19, wherein the first chemical component is non-toxic and the second chemical component is toxic.
- 24. (Original) A method according to claim 23, wherein the first chemical component comprises silicon and the second chemical component comprises arsenic.

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- 25. (Currently Amended) A method according to claim 19, further comprising after step bc) the steps of:
  - a. removing said at least one substrate from said enclosure;
  - b. cleaning said at least one substrate of any film deposited thereon;
  - c. installing said at least one substrate in said enclosure; and
  - again causing the first chemical component to be chemical vapor deposited onto said at least one substrate.
- 26. (New) A method of scrubbing an exhaust gas of a manufacturing process, the exhaust gas comprising a carrier gas and an n-type dopant gas, comprising the steps of:
  - a. flowing the exhaust gas through an enclosure defining a chamber and containing at least one substrate;
  - b. baffling, using said at least one substrate, the exhaust gas within said chamber so as to increase the residence time of the exhaust gas within said chamber; and
  - c. causing an n-doped layer of silicon to be chemical vapor deposited onto said at least one substrate.
- 27. (New) A method according to claim 26, further comprising the step of removing the n-type dopant gas from the exhaust gas after performing step c).
- 28. (New) A method according to claim 26, wherein step c) is performed by heating at least one of said at least one substrate and said enclosure to at least 800°C.
- 29. (New) A method according to claim 28, wherein step c) is performed by heating at least one of said at least one substrate and said enclosure to at least 1100°C.
- 30. (New) A method according to claim 26, wherein the carrier gas comprises silicon and the n-type dopant gas comprises arsenic.

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- 31. (New) A method according to claim 26, wherein said at least one substrate has a plurality of apertures and step b) is performed by causing the exhaust gas to flow substantially only through said plurality of apertures.
- 32. (New) A method according to claim 26, wherein said enclosure contains a plurality of substrates arranged in series with one another along said chamber so as to baffle flow of the exhaust gas.
- 33. (New) A method according to claim 32, wherein said plurality of substrates are arranged within said chamber so as to cause the exhaust gas to flow along a substantially serpentine path within said chamber.
- 34. (New) A method according to claim 32, wherein each of said plurality of substrates comprises a plurality of apertures and step b) is performed by causing the exhaust gas to flow substantially only through said plurality of apertures of each of said plurality of substrates.
- 35. (New) A method according to claim 19, wherein said at least one substrate has a plurality of apertures and step b) is performed by causing the exhaust gas to flow substantially only through said plurality of apertures.
- 36. (New) A method according to claim 19, wherein said enclosure contains a plurality of substrates arranged in series with one another along said chamber so as to baffle flow of the exhaust gas.
- 37. (New) A method according to claim 36, wherein said plurality of substrates are arranged within said chamber so as to cause the exhaust gas to flow along a substantially serpentine path within said chamber.

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38. (New) A method according to claim 36, wherein each of said plurality of substrates comprises a plurality of apertures and step b) is performed by causing the exhaust gas to flow substantially only through said plurality of apertures of each of said plurality of substrates.

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